

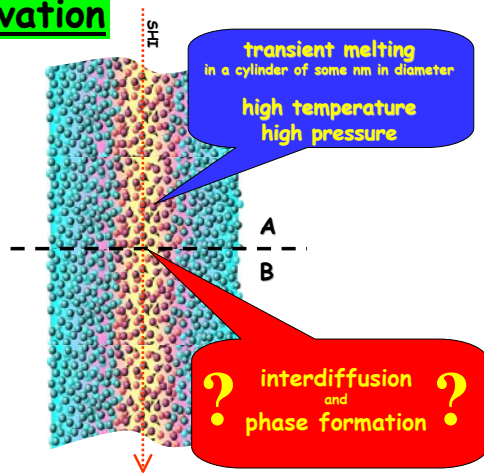
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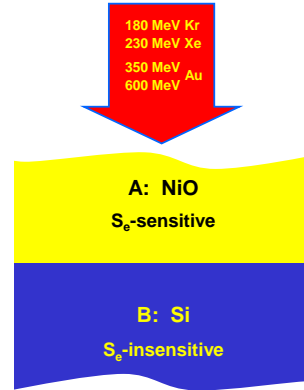
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Motivation



Experiment



Irradiation at 80 K:
Ionenstrahllabor (ISL) of
Hahn-Meitner Institut (HMI)

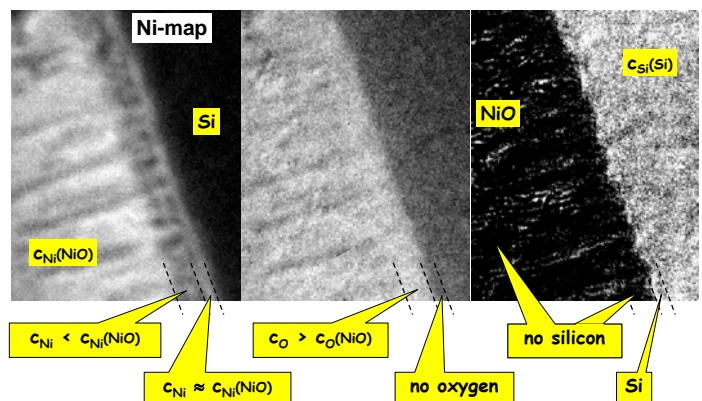
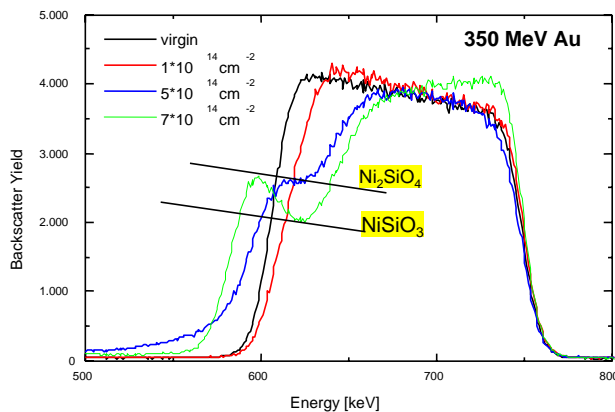
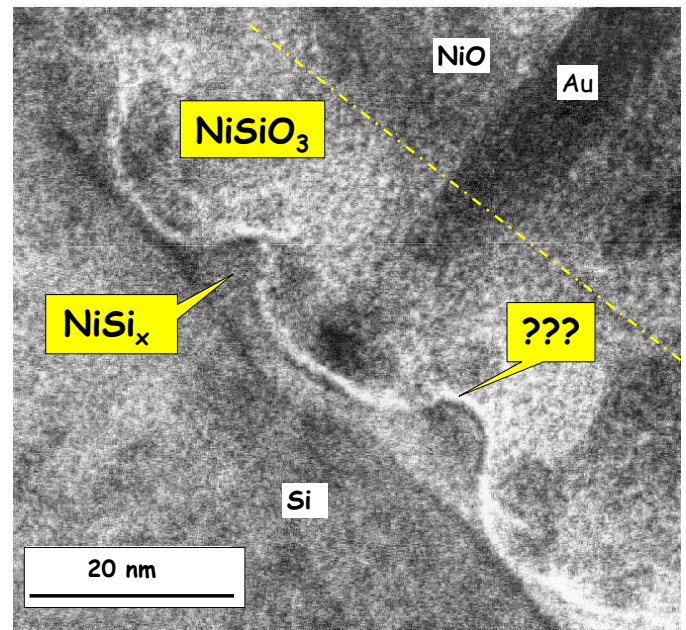
Analysis:

- RBS
Uni Stuttgart, Uni Jena
- TEM, EFTEM, EDX
HMI, Uni Augsburg

Results

According to RBS and TEM a complex interface structure develops upon irradiation. As can be seen in the TEM-image (10^{14} Au/cm² at 350 MeV), on top of the substrate an undulated layer forms, which according to EDX and EFTEM contains only Si and Ni and is thus attributed to a NiSi_x-phase also found in RBS ($x \approx 2$). This layer is sharply separated from a region containing Ni ($c_{Ni} < c_{Ni}^{NiO}$), O ($c_O > c_O^{NiO}$) and Si and which according to RBS is attributed to NiSiO₃ (lighter area). The nature of the boundary region between these two phases (undulated white line) is not yet clear. Finally, the Silicate is followed by stoichiometric NiO (darker area). The very dark 10 nm wide cylindrical areas in the NiO are due to Au, which has been trapped in the track of the latest ion impacts. It stems from a Au marker layer, which was included to visualize track formation. Remarkably, the troughs in the Silicide are always underneath such tracks, which suggests that the material is pushed to the side as by a stamp. This and the fact that NiSiO₃ (and also the spinel Ni₂SiO₄ modification) is a high-temperature high pressure phase clearly reflect the extreme non-equilibrium conditions in the excited ion track, which obviously govern the phase formation at the NiO/Si interface.

Cross Section TEM (XTEM)



Rutherford Backscattering Spectroscopy (RBS)

Energy-Filtered TEM (EFTEM)